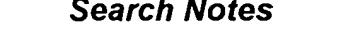


<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/765,991	HAMASAKI, YUJI
	<b>Examiner</b> Shih-wen Hsieh	<b>Art Unit</b> 2861

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner